



UM62256A Series

32K×8 CMOS SRAM

Features

- Single +5 volt power supply
- Access times: 70/100/120ns (max.)
- Current

Standard version: Operating: 70 mA (max.)

Standby: 2 mA (max.)

Low power version: Operating: 70 mA (max.)

Standby: $100 \mu A \text{ (max.)}$

Fully static operation, no clock or refreshing required

- Fully static operation, no clock or refreshing required
- Directly TTL compatible: All inputs and outputs
- Common I/O using three-state output
- Data retention voltage: 2V (min.) for low power version
- Available in 28 pin DIP or SOP packages (See ordering information)

General Description

The UM62256A is a high-speed, low-power 262,144-bit static random access memory organized as 32,768 words by 8 bits and operates on a single 5-volt power supply. It is built using UMC's high performance CMOS process.

Inputs and three-state outputs are TTL compatible and allow for direct interfacing with common system bus

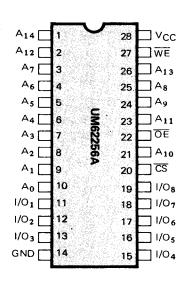
structures.

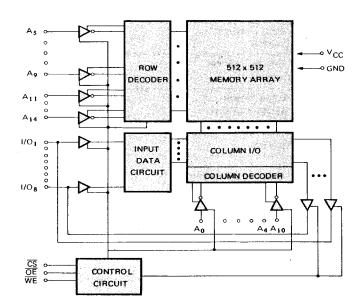
Minimum standby power is drawn by this device when $\overline{\text{CS}}$ is at a high level, independent of the other input levels.

Data retention is guaranteed at a power supply voltage as low as 2V for the low power version.

Pin Configuration

Block Diagram







Pin Description

Designation	Description
A ₀ - A ₁₄	Address Input
WE	Write Enable
ŌĒ	Output Enable
<u>cs</u>	Chip Select
1/01 - 1/08	Data Input/Output
Vcc	Power Supply (+5V)
GND	Ground

Absolute Maximum Ratings *

V _{CC} to GND
IN, IN/OUT Volt to GND -0.5 V to $V_{CC} + 0.5$ V
Operating Temperature, T _{opr} 0°C to +70°C
Storage Temperature, T _{stg} –55°C to +125°C
Temperature Under Bias, T _{bias} 10°C to +85°C
Power Dissipation, P _T 1.0W/SOP 0.7W
Soldering Temp. & Time

Recommended DC Operating Conditions

 $(T_A = 0^{\circ}C \text{ to } +70^{\circ}C)$

Symbol	Parameter	Min.	Тур.	Max.	Unit
V _{cc}	Supply Voltage	4.5	5.0	5.5	V
GND	Ground	0	0	0	V
V _{IH}	Input High Voltage	2.2	3.5	0.3V	٧
V _{IL}	Input Low Voltage	-0.3	0	+ 0.8	٧
CL	Output Load	_	_	100	pF
TTL	Output Load	-	_	1	_

*Comments

Stresses above those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only. Functional operation of this device at these or any other conditions above those indicated in the operational sections of this specification is not implied and exposure to absolute maximum rating conditions for extended periods may affect device reliability.

DC Electrical Characteristics $(T_A = 0^{\circ}C \text{ to } +70^{\circ}C, V_{CC} = 5V \pm 10\%, GND = 0V)$

Complete	Development		56A-70/ /12		56A-70L/ /12L	Unit	Conditions
Symbol	Parameter	Min.	Max.	Min.	Max.	Oint	Conditions
[]	Input Leakage Current	_	2		2	μΑ	V_{IN} = GND to V_{CC}
I _{LO}	Output Leakage Current	-	2	_	2	μΑ	$\overline{CS} = V_{IH} \text{ or } \overline{OE} = V_{IH}$ $V_{I/O} = \text{GND to } V_{CC}$
¹ cc	Active Power Supply Current	_	15	_	15	mA	$\overline{\text{CS}} = V_{1L}, I_{1/O} = 0 \text{ mA}$
l _{CC1}	Dynamic Operating Current	_	70	_	70	mA	$\frac{\text{Min. Cycle, Duty} = 100\%}{\overline{\text{CS}}} = V_{1L}, I_{1/O} = 0 \text{ mA}$
CC ₂	Dynamic Operating Current	_	15	_	15	mA	$\overline{CS} = V_{1L}, V_{1H} = V_{CC}$ $V_{1L} = 0V, f = 1 MHz$ $I_{1/O} = 0 mA$
I _{SB}		_	3		3	mA	CS = V _{1H}
SB ₁	Standby Power Supply Current	_	2	_	0.1	mA	$\overline{CS} \geqslant V_{CC} - 0.2V$ $V_{IN} \geqslant V_{CC} - 0.2V \text{ or }$ $V_{IN} \leqslant 0.2V$
V _{OL}	Output Low Voltage	_	0.4	_	0.4	٧	I _{OL} = 2.1 mA
V _{OH}	Output High Voltage	2.4	_	2.4		V	I _{OH} = -1.0 mA



Truth Table

Mode	<u>cs</u>	ŌĒ	WE	I/O Operation	Supply Current
Standby	Н	X	X	High Z	I _{SB} , I _{SB1}
Output Disable	L	Н	Н	High Z	I _{CC} , I _{CC1} , I _{CC2}
Read	L	L	н	D _{OUT}	¹ cc, ¹ cc1, ¹ cc2
Write	L	X	L	D _{IN}	1 _{CC} , 1 _{CC1} , 1 _{CC2}

Note: X:H or L

Capacitance $(T_A = 25^{\circ}C, f = 1.0 \text{ MHz})$

Symbol	Parameter	Min.	Max.	Unit	Test Conditions
C _{IN} *	Input Capacitance		6	рF	V _{IN} = 0V
C _{1/O} *	Input/Output Capacitance		8	pF.	V _{I/O} = 0V

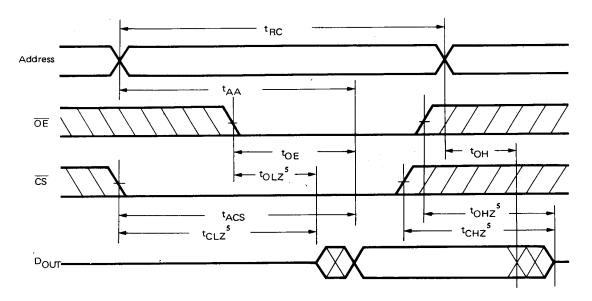
^{*} This parameter is sampled and not 100% tested.

AC Electrical Characteristics $(T_A = 0^{\circ}C \text{ to } +70^{\circ}C, V_{CC} = 5V \pm 10\%)$

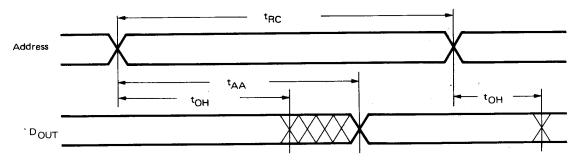
Symbol	Parameter		256-10 256-10L Max.		256-12 256-12 L Max.		256-15 256-15L Max.	Unit
Read Cycl	e							
t _{RC}	Read Cycle Time	100		120	_	150	_	ns
t _{AA}	Address Access Time	-	100	_	120	_	150	ns
t _{ACS}	Chip Select Access Time		100	_	120		150	ns
t _{OE}	Output Enable to Output Valid	_	50	_	60	-	70	ns
^t CLZ	Chip Selection to Output in Low Z	10	_	10	_	10	_	ns
^t olz	Output Enable to Output in Low Z	5	_	5		5	_	ns
t _{CHZ}	Chip Deselection to Output in High Z	0	35	0	40	0	50	ns
t _{OHZ}	Output Disable to Output in High Z	Ö	35	0	40	0	50	ns
^t oн	Output Hold from Address Change	10		10	_	10	_	ns
Write Cycl	e					•		
t _{WC}	Write Cycle Time	100	_	120	· -	150	_	ns
^t cw	Chip Selection to End of Write	80	_	85		100	_	ns
t _{AS}	Address Set up Time of Write	0	_	0	_	0	_	ns
^t AW	Address Valid to End of Write	80	_	85	-	100	_	ns
t _{WP}	Write Pulse Width	60	_	70		90	_	ns
twR	Write Recovery Time	0	_	0	_	0	_	ns
^t wHZ	Write to Output in High Z	0	35	0	40	0	50	ns
t _{DW}	Data to Write Time Overlap	40		50		60	_	ns
t _{DH}	Data Hold from Write Time	0	_	0	_	0	_	ns
^t ohz	Output Disable to Output in High Z	0	35	0	40	0	50	ns
tow	Output Active from End of Write	10	-	10		10	_	ns



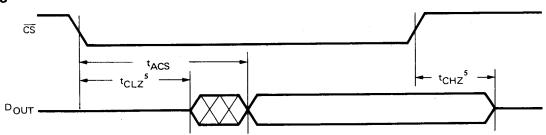
Timing Waveforms Read Cycle No. 1⁽¹⁾



Read Cycle 2^(1, 2, 4)

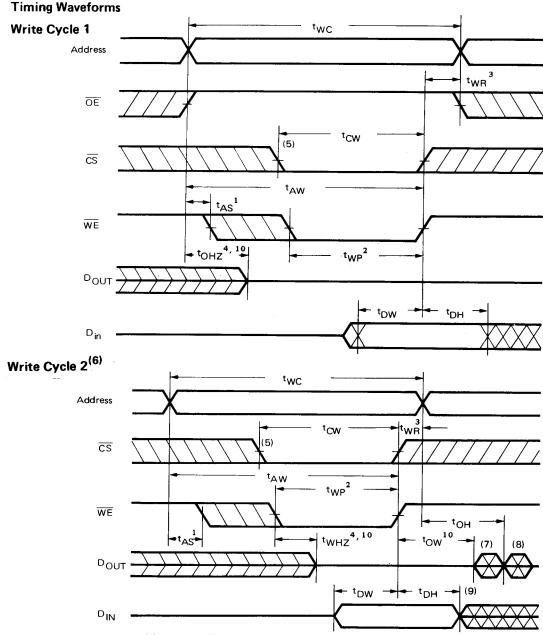


Read Cycle 3^(1, 3, 4)



- Notes: 1. WE is High for Read Cycle.
 2. Device is continuously selected, CS = V_{1L}.
 - Address valid prior to or coincident with $\overline{\text{CS}}$ transition low.
 - $\overline{OE} = V_{IL}$.
 - 5. Transition is measured ± 500mV from steady state. This parameter is sampled and not 100% tested.





- Notes: 1. tas is measured from the address valid to the beginning of write.
 - 2. A write occurs during the overlap (t_{WP}) of a low \overline{CS} and a low \overline{WE} .
 - 3. t_{WR} is measured from the earlier of \overline{CS} or \overline{WE} going high to the end of write cycle.
 - 4. During this period, I/O pins are in the output state so that the input signals of opposite phase to the outputs must not be applied.
 - 5. If the CS low transition occurs simultaneously with the WE low transition or after the WE transition, outputs remain in a high impedance state.
 - 6. \overline{OE} is continuously low ($\overline{OE} = V_{11}$).
 - 7. $D_{\mbox{\scriptsize OUT}}$ is the same phase of write data of this write cycle.
 - 8. D_{OUT} is the read data of next address.
 - 9. If \overline{CS} is low during this period, I/O pins are in the output state. Data input signals of opposite phase to the outputs must not be applied to them at this time.
 - 10. Transition is measured ± 500mV from steady state. This parameter is sampled and not 100% tested.



AC Test Conditions

Input Pulse Levels	0.8V to 2.2V
Input Rise and Fall Times	5 ns
Input and Output	
Timing Reference Levels	1.5V
Output Load	See Fig. 1, 2

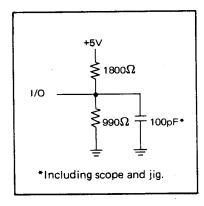


Figure 1. Output Load

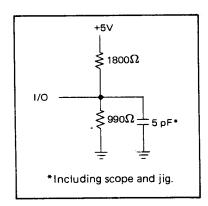


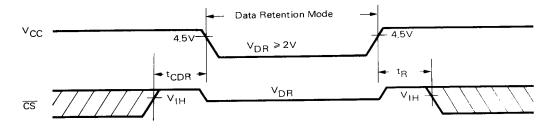
Figure 2. Output Load for t_{CLZ} , t_{OLZ} , t_{CHZ} , t_{OHZ} , t_{WHZ} , and t_{OW}

Data Retention Characteristics $(T_A = 0^{\circ}C \text{ to } +70^{\circ}C; \text{ L version only})$

Symbol	Parameter	Min.	Max.	Unit	Test Conditions
V _{DR}	V _{CC} for Data Retention	2.0	5.5	V	$\overline{\text{CS}} \geqslant V_{\text{CC}} - 0.2V$
CCDR	Data Retention Current	_	50	μΑ	$V_{CC} = 3.0V$, $\overline{CS} \ge V_{CC} - 0.2V$ $V_{IN} \ge V_{CC} - 0.2V$ or $V_{IN} \le 0.2V$
t _{CDR}	Chip Deselect to Data Retention Time	0	-	ns	See Retention
t _R	Operation Recovery Time	t _{RC} *	_	ns	Waveform

^{*}t_{RC} = Read Cycle Time

Timing Waveform Low V_{CC} Data Retention Waveform





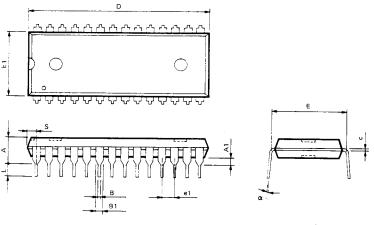
Ordering Information

Part No.	Access Time (ns)	Operating Current Max. (mA)	Standby Current Max. (mA)	Package
UM62256A-10	100 ns	70	2	28L DIP
UM62256A-10L	100 ns	70	0.1	28L DIP
UM62256AM-10	100 ns	70	2	28L SOP
UM62256AM-10L	100 ns	70	0.1	28L SOP
UM62256A-12	120 ns	70	2	28L DIP
UM62256A-12L	120 ns	70	0.1	28L DIP
UM62256AM-12	120 ns	70	2	28L SOP
UM62256AM-12L	120 ns	70	0.1	28L SOP
UM62256A-15	150 ns	70	2	28L DIP
UM62256A-15L	150 ns	70	0.1	28L DIP
UM62256AM-15	150 ns	70	2	28L SOP
UM62256AM-15L	150 ns	70	0.1	28L SOP

Package Information

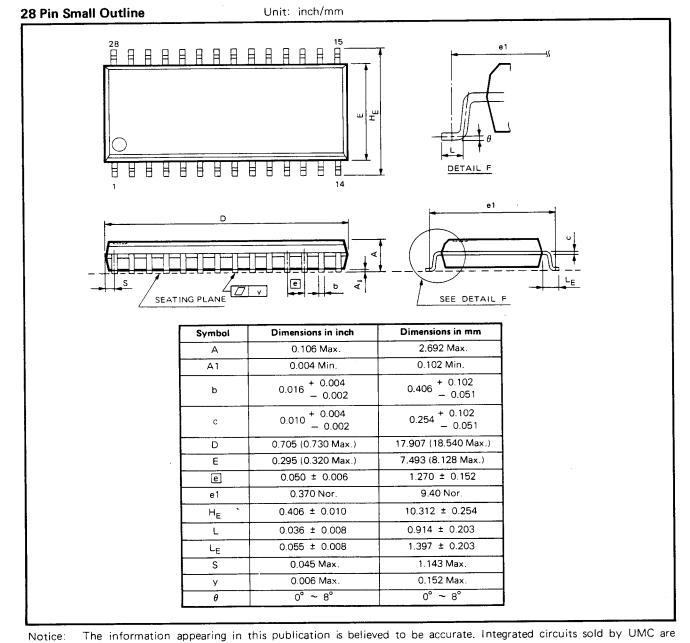
28 LEAD DUAL IN-LINE; PLASTIC

Unit: inch/mm



Symbol	Dimensions in inch	Dimensions in mm
Α	0.210 Max.	5.334 Max.
A1	0.010 Min.	0.254 Min.
В	0.018 + 0.004 - 0.002	0.457 + 0.102 - 0.051
B1	0.060 + 0.004 - 0.002	1.524 + 0.102 - 0.051
С	0.010 + 0.004 - 0.002	0.254 + 0.102 - 0.051
D	1.460 (1.470 Max.)	37.084 (37.338 Max.)
ć	0.600 ± 0.010	15.240 ± 0.254
E1	0.545 (0.575 Max.)	13.843 (14.605 Max.)
e1	0.100 ± 0.010	2.540 ± 0.254
L	0.130 ± 0.010	3.302 ± 0.254
α	0° ~ 15°	0° ~ 15°
S	0.090 Max.	2.286 Max



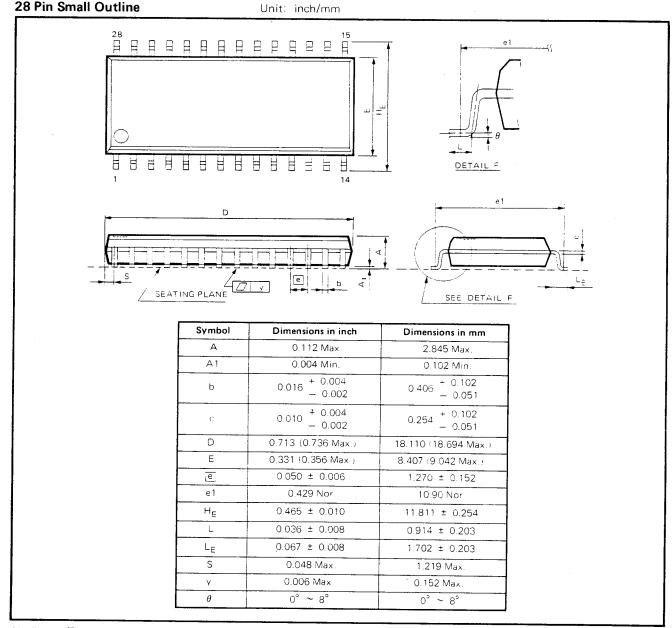


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